



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.	10/090,287	Confirmation No.	6609
First Inventor	Peter G. Borden	Filing Date	March 1, 2002
Tech. Center/ Art Unit	2859	Examiner	Verbitsky, Gail
Title:	Identifying Defects In A Conductive Structure Of A Wafer, Based On Heat Transfer Therethrough		
Docket No.:	BOX014 US	Customer No.:	34036

Santa Clara, California  
December 23, 2003

COMMISSIONER FOR PATENTS  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT**

Dear Sir:

In response to Office Action dated September 25, 2003, please amend the above-identified application as follows.

**Amendments to the Claims** begin on page 2 of this paper.

**Remarks/Arguments** begin on page 10 of this paper.

01/02/2004 ADD01 00000013 10090287

01 FC:1201  
02 FC:1202

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90.00 OP

TECHNOLOGY CENTER 2800

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